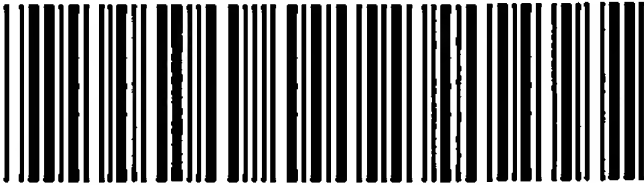


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/649,198	KOUGIOURIS ET AL.	
	Examiner	Art Unit	
	Maikhanh Nguyen	2176	

SEARCHED			
Class	Subclass	Date	Examiner
715	513	8/20/2005	MK
	526,531	8/20/2005	MK
715	700,760	8/20/2005	MK
	861	8/20/2005	MK
709	203	8/20/2005	MK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventor Name Search	8/20/2005	MK
West Search (See search history printout)	8/20/2005	MK
NPL (IEEE)	8/20/2005	MK